



**AUDIX CORPORATION**

**TECHNICAL DIVISION EMC DEPARTMENT**

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# Technical Compliance Statement

No. ATM-E92103

The following products has been tested by us with the listed standards and found in compliance with the council EMC directive 89/336/EEC. It is possible to use CE marking to demonstrate the compliance with this EMC Directive.

**Submittor** : **FSP Group Inc.**  
**No. 22, Jianguo E. Rd., Taoyuan City,**  
**Taiwan, R.O.C.**

**Product** : **Switching Power Supply**  
**M/N FSP270-50SNV**

Test Standards		
EN 55022/1998	Limits and methods of measurement of radio disturbance characteristics of information technology equipment	
EN 61000-3-2/1995 +A1/1998 +A2/1998 +A14/2000	Part 3 : Limits -Section 2 : Limits for harmonic current emission (equipment input current <=16A phase)	
EN 61000-3-3/1995 +A1/2001	Part 3 : Limits-Section 3 : Limitation of voltage fluctuations and flicker in low-voltage supply systems for equipment with rated current <=16A	
EN 55024/1998	Information technology equipment-Immunity characteristics Limits and methods of measurement	
	IEC 61000-4-2/1995 +A1/1998+A2/2000	Electrostatic discharge immunity test
	IEC 61000-4-3/1995	Radiated, radio-frequency electromagnetic field immunity test
	IEC 61000-4-4/1995	Electrical fast transient / burst immunity test
	IEC 61000-4-5/1995	Surge immunity test
	IEC 61000-4-6/1996	Immunity to conducted disturbances, induced by radio-frequency fields
	IEC 61000-4-8/1993	Power frequency magnetic field immunity test
	IEC 61000-4-11/1994	Voltage dips, short interruptions and voltage variations immunity tests



*Leon Liu May 14 2003*  
Leon Liu / Manager

The verification is based on a single evaluation of one sample of above mentioned products. It does not imply an assessment of the whole production and does not permit the use of the test lab. logo.